## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10736612	SUZUKAWA, HIROKI
Examiner	Art Unit
Schmidt, Kari L	2139

SEARCHED					
Class	Subclass	Date	Examiner		
713	182	8/27/2007	Kari Schmidt		
713	168	8/27/2007	Kari Schmidt		
703	whole class	8/27/2007	Kari Schmidt		
340	573.1	8/27/2007	Kari Schmidt		

SEARCH NOTES				
Search Notes	Date	Examiner		
Inventor Search (eDAN and PALM)	8/27/2007	Kari Schmidt		
340/573.1 keyword search: "proximity and RFID" and "proximity and RFID and security"	8/27/2007	Kari Schmidt		
Google Search: badge and proximity and RFID	8/27/2007	Kari Schmidt		
Google Search: proximity access control and IBM and security	8/27/2007	Kari Schmidt		
Google Search: reticle of wafer	8/27/2007	Kari Schmidt		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		

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